捷多邦,专业PCB**·SN54AH@T@44章SN7**4AHCT244 OCTAL BUFFERS/DRIVERS WITH 3-STATE OUTPUTS

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- EPIC™ (Enhanced-Performance Implanted CMOS) Process
- Inputs Are TTL-Voltage Compatible
- Latch-Up Performance Exceeds 250 mA Per JESD 17
- Package Options Include Plastic Small-Outline (DW), Shrink Small-Outline (DB), Thin Very Small-Outline (DGV), Thin Shrink Small-Outline (PW), and Ceramic Flat (W) Packages, Ceramic Chip Carriers (FK), and Standard Plastic (N) and Ceramic (J) DIPs

description

These octal buffers/drivers are designed specifically to improve both the performance and density of 3-state memory-address drivers, clock drivers, and bus-oriented receivers and transmitters.

The 'AHCT244 devices are organized as two 4-bit buffers/line drivers with separate output-enable (OE) inputs. When OE is low, the device passes data from the A inputs to the Y outputs. When OE is high, the outputs are in the high-impedance state.

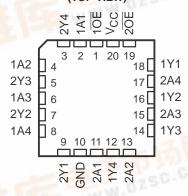
To ensure the high-impedance state during power up or power down, \overline{OE} should be tied to V_{CC} through a pullup resistor; the minimum value of the resistor is determined by the current-sinking capability of the driver.

The SN54AHCT244 is characterized for operation over the full military temperature range of -55°C to 125°C. The SN74AHCT244 is characterized for operation from -40°C to 85°C.

SN54AHCT244 . . . J OR W PACKAGE SN74AHCT244 . . . DB, DGV, DW, N, OR PW PACKAGE (TOP VIEW)

1 <mark>OE</mark>	d	1	U	20] V _{CC}
1A1		2		19] 20E
2Y4		3		18] 1Y1
1A2		4		17	2A4
2Y3		5		16	1Y2
1A3	d	6		15	2A3
2Y2	d	7		14	1Y3
1A4		8		13	2A2
2Y1		9		12] 1Y4
GND	4	10		11	2A1

SN54AHCT244 . . . FK PACKAGE (TOP VIEW)



FUNCTION TABLE (each 4-bit buffer/driver)

(odon i bit banonanivor)							
INP	JTS	OUTPUT					
OE	Α	Υ					
L	Н	H					
L	L	L					
Н	Χ	Z					

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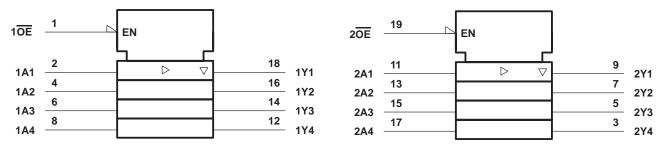




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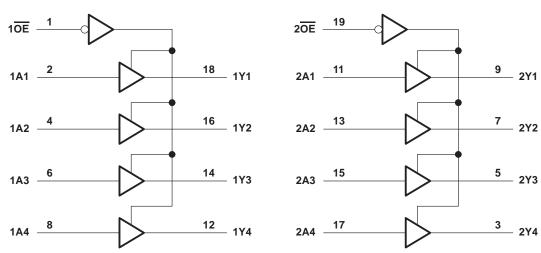
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logic symbol†



[†] This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

logic diagram (positive logic)



absolute maximum ratings over operating free-air temperature range (unless otherwise noted)‡

Supply voltage range, V _{CC}		0.5 V to 7 V
Input voltage range, V _I (see Note 1)		–0.5 V to 7 V
Output voltage range, VO (see Note 1)		1.000000000000000000000000000000000000
Input clamp current, I_{IK} ($V_I < 0$)		
Output clamp current, I_{OK} ($V_O < 0$ or $V_O > V_{CO}$	c)	±20 mA
Continuous output current, $I_O(V_O = 0 \text{ to } V_{CC})$		±25 mA
Continuous current through V _{CC} or GND		±75 mA
Package thermal impedance, θ _{JA} (see Note 2)	: DB package	70°C/W
-	DGV package	92°C/W
	DW package	58°C/W
	N package	69°C/W
	PW package	83°C/W
Storage temperature range, T _{sto}		–65°C to 150°C

[‡] Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.



NOTES: 1. The input and output voltage ratings may be exceeded if the input and output current ratings are observed.

^{2.} The package thermal impedance is calculated in accordance with JESD 51.

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recommended operating conditions (see Note 3)

		SN54AH	CT244	SN74AH	UNIT	
		MIN	MAX	MIN	MAX	UNIT
Vcc	Supply voltage	4.5	5.5	4.5	5.5	V
VIH	High-level input voltage	2		2		V
V _{IL}	Low-level input voltage		0.8		0.8	V
VI	Input voltage	0	5.5	0	5.5	V
Vo	Output voltage	0	VCC	0	VCC	V
IOH	High-level output current		-8		-8	mA
loL	Low-level output current		8		8	mA
TA	Operating free-air temperature	- 55	125	-40	85	°C

NOTE 3: All unused inputs of the device must be held at V_{CC} or GND to ensure proper device operation. Refer to the TI application report, *Implications of Slow or Floating CMOS Inputs*, literature number SCBA004.

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CONDITIONS	Vaa	Τ _Δ	√ = 25°C	;	SN54AH	CT244	SN74AH	UNIT		
PARAMETER	TEST CONDITIONS	Vcc	MIN	TYP	MAX	MIN	MAX	MIN	MAX	UNII	
V	ΙΟΗ = -50 μΑ	4.5 V	4.4	4.5		4.4		4.4		٧	
VOH	I _{OH} = -8 mA	4.5 V	3.94			3.8		3.8			
\/	I _{OL} = 50 μA	4.5 V			0.1		0.1		0.1	V	
VOL	I _{OL} = 8 mA	4.5 V			0.36		0.44		0.44	V	
loz	$V_O = V_{CC}$ or GND	5.5 V			±0.25		±2.5		±2.5	μΑ	
lį	$V_I = V_{CC}$ or GND	0 V to 5.5 V			±0.1		±1*		±1	μΑ	
Icc	$V_I = V_{CC}$ or GND, $I_O = 0$	5.5 V			4		40		40	μΑ	
ΔI _{CC} †	One input at 3.4 V, Other inputs at V _{CC} or GND	5.5 V			1.35		1.5		1.5	mA	
Ci	V _I = V _{CC} or GND	5 V		2.5	10				10	pF	
Co	$V_O = V_{CC}$ or GND	5 V	_	3						pF	

^{*} On products compliant to MIL-PRF-38535, this parameter is not production tested at $V_{CC} = 0 \text{ V}$.



[†] This is the increase in supply current for each input at one of the specified TTL voltage levels rather than 0 V or VCC.

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switching characteristics over recommended operating free-air temperature range, V_{CC} = 5 V \pm 0.5 V (unless otherwise noted) (see Figure 1)

PARAMETER	FROM	то	LOAD	T	λ = 25°C	;	SN54AH	CT244	SN74AH	CT244	UNIT
PARAWIETER	(INPUT)	(OUTPUT)	CAPACITANCE	MIN	TYP	MAX	MIN	MAX	MIN	MAX	UNIT
tPLH	А	Y	C _L = 15 pF		5.4*	7.4*	1*	8.5*	1	8.5	ns
t _{PHL}	Α	'	CL = 13 μ		5.4*	7.4*	1*	8.5*	1	8.5	115
^t PZH	<u>OE</u>	Υ	C _L = 15 pF		7.7*	10.4*	1*	12*	1	12	ns
t _{PZL}	OE	'	CL = 13 μ		7.7*	10.4*	1*	12*	1	12	115
^t PHZ	ŌĒ	Y	C _L = 15 pF		5*	9.4*	1*	10*	1	10	ns
t _{PLZ}		'	OL = 13 pi		5*	9.4*	1*	10*	1	10	113
t _{PLH}	А	Y	C: 50 pF		5.9	8.4	1	9.5	1	9.5	
t _{PHL}		^	Ť	C _L = 50 pF		5.9	8.4	1	9.5	1	9.5
t _{PZH}		Y	C 50 pF		8.2	11.4	1	13	1	13	ns
t _{PZL}	OE	OE Y	$C_L = 50 \text{ pF}$		8.2	11.4	1	13	1	13	115
t _{PHZ}	ŌĒ	Y	C _L = 50 pF		8.8	11.4	1	13	1	13	ns
tPLZ		1	CL = 50 pr		8.8	11.4	1	13	1	13	115
tsk(o)			C _L = 50 pF			1**				1	ns

^{*} On products compliant to MIL-PRF-38535, this parameter is not production tested.

noise characteristics, $V_{CC} = 5 \text{ V}$, $C_L = 50 \text{ pF}$, $T_A = 25^{\circ}\text{C}$ (see Note 4)

PARAMETER -				SN74AHCT244		
				MAX	UNIT	
V _{OH(V)}	Quiet output, minimum dynamic V _{OH}		4.1		V	
V _{IH(D)}	High-level dynamic input voltage	2			V	
V _{IL(D)}	Low-level dynamic input voltage			0.8	V	

NOTE 4: Characteristics are for surface-mount packages only.

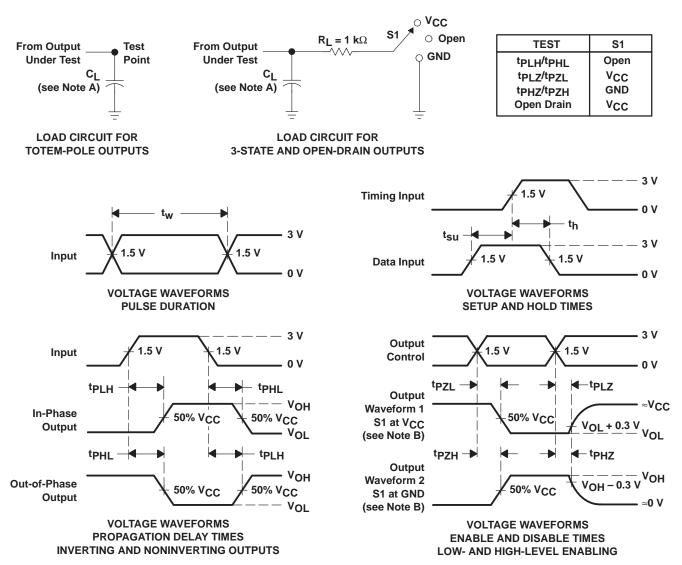
operating characteristics, $V_{CC} = 5 \text{ V}$, $T_A = 25^{\circ}\text{C}$

PARAMETER		TEST C	ONDITIONS	TYP	UNIT
C _{pd}	Power dissipation capacitance	No load,	f = 1 MHz	8.2	pF

^{**} On products compliant to MIL-PRF-38535, this parameter does not apply.

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PARAMETER MEASUREMENT INFORMATION



NOTES: A. C_I includes probe and jig capacitance.

- B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
- C. All input pulses are supplied by generators having the following characteristics: PRR \leq 1 MHz, $Z_Q = 50 \Omega$, $t_f \leq 3$ ns, $t_f \leq 3$ ns.
- D. The outputs are measured one at a time with one input transition per measurement.

Figure 1. Load Circuit and Voltage Waveforms



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